Notice of References Cited					Application/Control No. 09/560,268 Examiner DuyVů n Deo		Applicant(s)/Patent Under Reexamination LEE ET AL.		
							Art Unit		
							1765	Page 1 of 1	
U.S. PATENT DOCUMENTS DOCUMENT									
*		DOCUMENT NO.	DATE		NAME	CLASS	SUBCLASS	SOURCE	**
				Hayashi at al		420		APS	OTHER
	Α	5,482,895	Jan. 1996	Hayashi et al.		438	620		
	В	4,915,781	Apr. 1990	Bohnen et al.		216	107		
	С	4,875,973	Oct. 1989	Heikkila et al.		216	107		
	D	4,857,972	Oct. 1989	Williams et	al.	257	18		
	E	3,773,577	Nov. 1973	Shibasaki et al.		216	106		
	F								
	O								
	н								
	J								
	к								
	L								
	м								
		FOREIGN PATENT DOCUMENTS							NT
*		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS	DOCUMENT SOURCE ** APS OTHER	
								 	
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	Р								
	Q								
	R								
	s								
	Т								
NON-PATENT DOCUMENTS									NT
*		DOCUMENT (Including Author, Title Date, Source, and Pertinent Pages)						SOURCE	
							APS	OTHER	
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*A copy of this reference is not being furnished with this Office action. (See Manual of Patent Examining Procedure, Section 707.05(a).)
**APS encompasses any electronic search i.e. text, image, and Commercial Databases.
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Notice of References Cited

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